THE WORLD COMES HERE

TMS 2026

155th Annual Meeting & Exhibition

March 15–19, 2026
San Diego Convention Center
and Hilton San Diego Bayfront
San Diego, California, USA
#TMSAnnualMeeting

SUBMIT AN ABSTRACT FOR THE FOLLOWING SYMPOSIUM

ADVANCED CHARACTERIZATION METHODS

Recent Advances in Electron Back-Scattered Diffraction and Related Techniques

This symposium focuses on the use of Electron Backscattered Diffraction (EBSD) in the Scanning Electron Microscope (SEM) but contributions on related SEM based diffraction techniques are also encouraged including Transmission Kikuchi Diffraction (TKD), Electron Channeling Patterns (ECP), Electron Channeling Contrast Imaging (ECCI) and 4DSTEM in the SEM.

We invite contributions in the following areas:
- Advances in theory, modeling, indexing and interpretation of diffraction patterns.
- Novel analysis and quantitative metrics of SEM based diffraction data
- Advances in detector systems, including direct electron detection
- Developments in data collection strategies to enhance the efficiency and accuracy of SEM-based techniques
- SEM based diffraction applications in Materials Science
- SEM based diffraction applications in the Earth Sciences

SPONSORED BY:
TMS Structural Materials Division; TMS Advanced Characterization, Testing, and Simulation Committee

ORGANIZED BY:
- **Stuart Wright,** EDAX
- **Andrew Polonsky,** Sandia National Laboratories
- **Alice Bastos da Silva Fanta,** DTU Technical University of Denmark

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QUESTIONS?
Contact programming@tms.org